

1. Scope

The present specifications shall apply to an RD2A.

2. Outline

Type	Silicon Diode
Structure	Resin Molded
Applications	High Frequency Rectification

3. Flammability

UL94V-0(Equivalent)

Not Recommended for New Designs

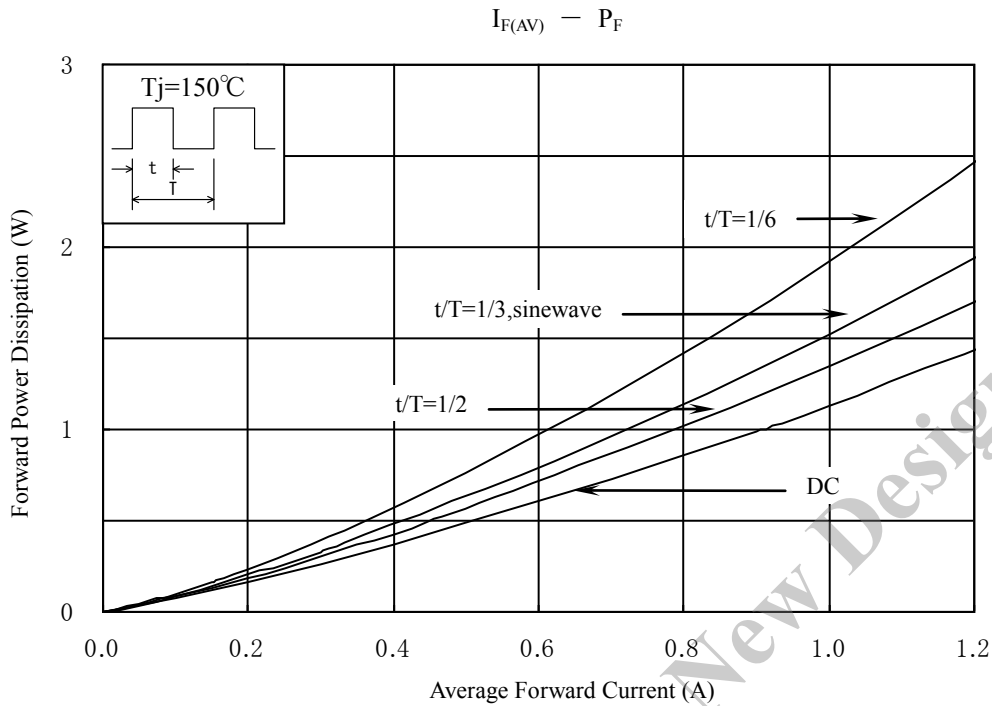
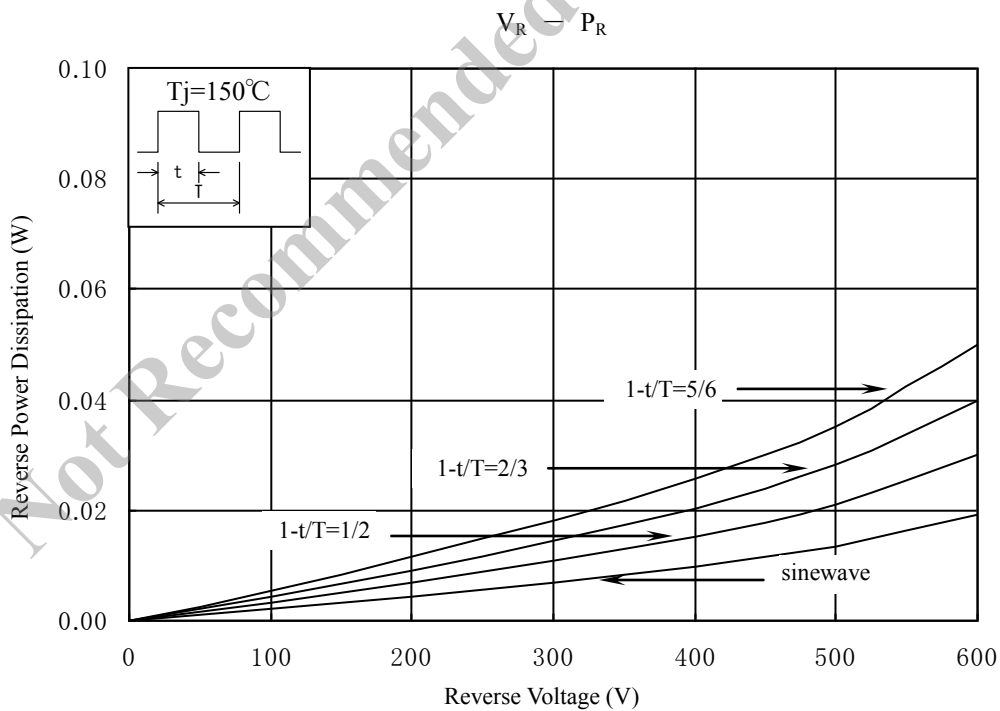
4. Absolute maximum ratings

No.	Item	Symbol	Unit	Rating	Conditions
1	Transient Peak Reverse Voltage	V_{RSM}	V	600	
2	Peak Reverse Voltage	V_{RM}	V	600	
3	Average Forward Current	$I_{F(AV)}$	A	1.2	Refer to Derating of 7
4	Peak Surge Forward Current	I_{FSM}	A	30	10msec. Half sinewave, one shot
5	I^2t Limiting Value	I^2t	A^2s	4.5	$1\text{msec} \leq t \leq 10\text{msec}$
6	Junction Temperature	T_j	$^{\circ}\text{C}$	-40~+150	
7	Storage Temperature	T_{stg}	$^{\circ}\text{C}$	-40~+150	

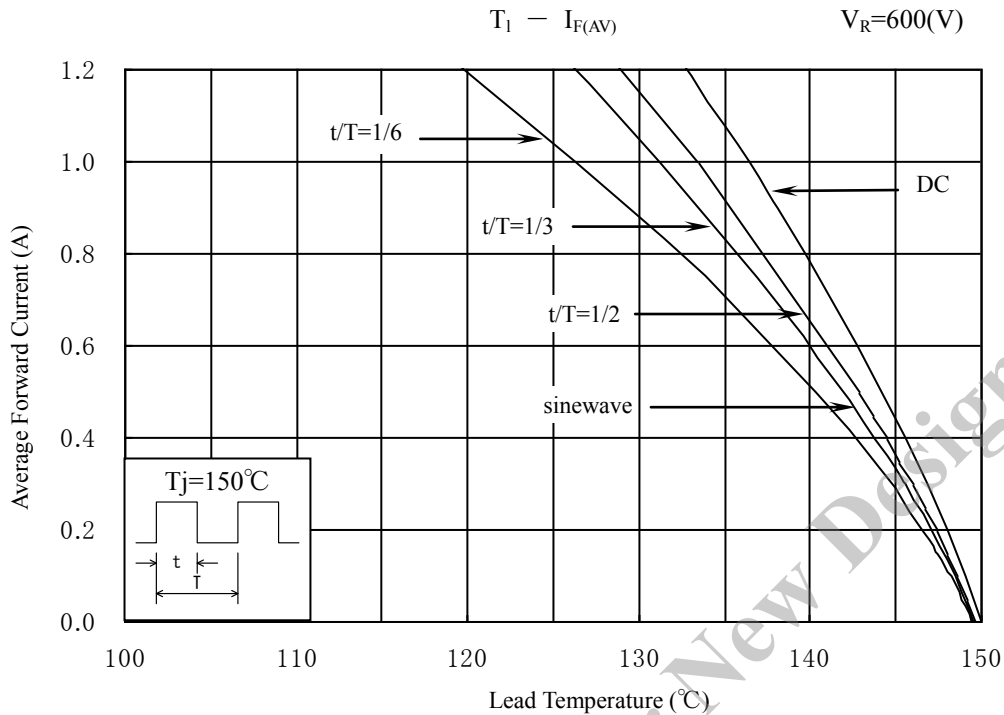
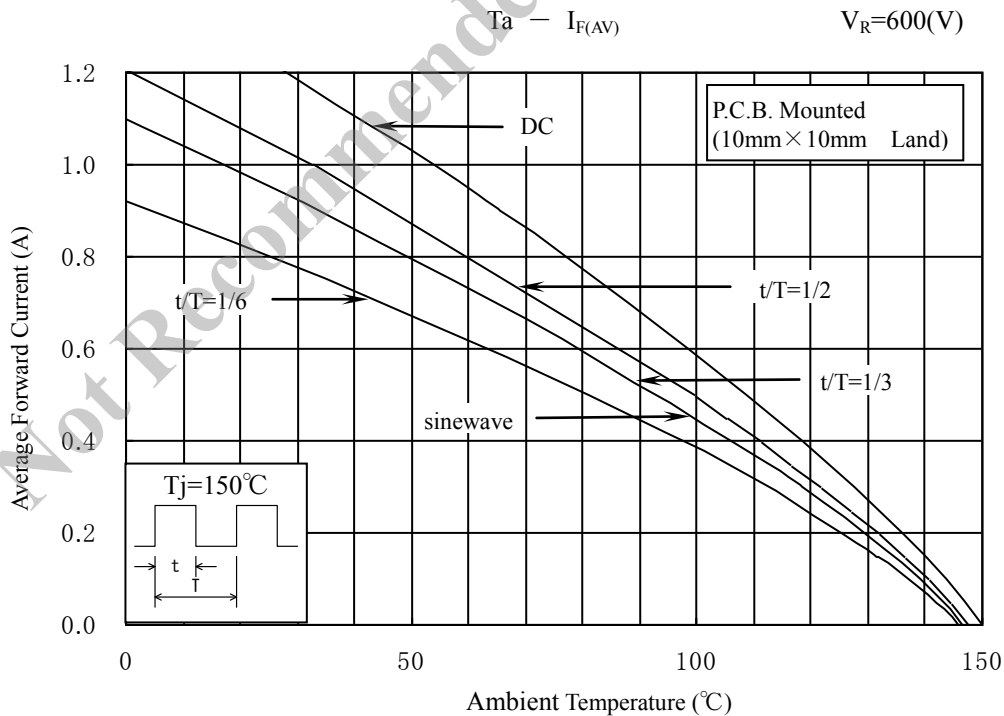
5. Electrical characteristics

No.	Item	Symbol	Unit	Value	Conditions
1	Forward Voltage Drop	V_F	V	1.55 max.	$I_F=1.2\text{A}$
2	Reverse Leakage Current	I_R	μA	50 max.	$V_R=V_{RM}$
3	Reverse Leakage Current Under High Temperature	$H \cdot I_R$	μA	100 max.	$V_R=V_{RM}$, $T_j=150^{\circ}\text{C}$
4	Reverse Recovery Time	t_{rr1}	ns	50 max.	$I_F=I_{RP}=100\text{mA}$ 90% Recovery point, $T_j=25^{\circ}\text{C}$
		t_{rr2}	ns	35 max.	$I_F=100\text{mA}$, $I_{RP}=200\text{mA}$ 75% Recovery point, $T_j=25^{\circ}\text{C}$
5	Thermal Resistance	$R_{th(j-l)}$	$^{\circ}\text{C/W}$	12 max.	Between Junction and Lead

6. Characteristics

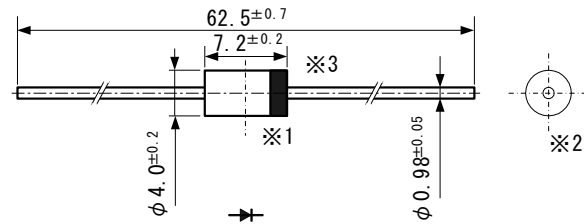


7. Derating



8. Package information

8-1 Package type, physical dimensions and material



- ※1 The allowance position of Body against the center of whole lead wire is 0.5mm(max.)
※2 The centric allowance of lead wire against center of physical body is 0.3mm(max.)
※3 The burr may exit up to 2mm from the body of lead

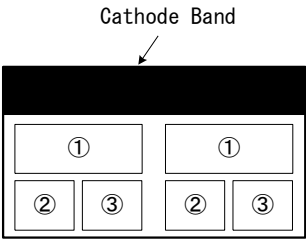
Dimensions in mm

8-2 Appearance

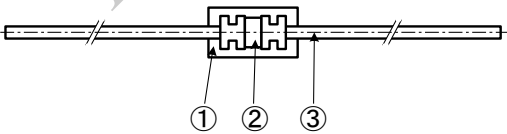
The body shall be clean and shall not bear any stain, rust or flaw.

8-3 Marking

- ① Type number RD2A
② Lot number 1
First digit: Last digit of Year
Second digit: Month
From 1 to 9 for Jan. to Sep.
O for Oct., N for Nov., and D for Dec.
③ Lot number 2 (ten days)
· : Top of the month
· · : Middle of month
· · · : End of month



9. Internal structure diagram



No.	Name of part	Materials
①	Plastic body	Epoxy Resin
②	Chip	Silicon
③	Leads	Solder Dipped Silver plated copper wire

10. Reliability

No.	Item	Rating	Conditions
1	Thermal Fatigue Test	5000 cycles	$\Delta T_j = 100^\circ\text{C}$
2	High Temperature Reverse Bias Test	1000 hours	$T_a = 150^\circ\text{C}$, $V_R = V_{RM}$ (Half sine wave)
3	Humidity Reverse Bias Test	500 hours	$T_a = 85^\circ\text{C}$, R.H.=85%, $V_R = V_{RM} \times 0.8$ (D.C.)
4	High Temperature Storage Test	1000 hours	$T_a = 150^\circ\text{C}$
5	Moisture Resistance Test	1000 hours	$T_a = 85^\circ\text{C}$, 85% R.H.
6	Thermal Shock Test	100 cycle	Ice-water(5min.) ~ R.T.(20sec.) ~ Boiling-water(5min.)
7	Temperature Cycle Test	100 cycle	-40°C (30min.) ~ $+150^\circ\text{C}$ (30min.)
8	Pressure Cooker Test	96 hours	$2.03 \times 10^5 \text{Pa}$, 100% R.H., Unsaturated equipment
9	Resistance to Soldering Heat Test	10 sec.	$260 \pm 5^\circ\text{C}$, Dipping up to 1.5mm from case
		3.5 sec.	$380 \pm 5^\circ\text{C}$, Using soldering iron
10	Solderability Test	95%	$245 \pm 5^\circ\text{C}$, $5 \pm 0.5 \text{sec.}$, Using rosin flux
11	Lead Bend Test	2 cycles	Apply EIAJ ED-4701 A-111
12	Lead Pull Test	10 sec.	
13	Lead Twist Test	2 times	
14	Drop Test	10 times	Naturally drop from 1m height on maple plate

Acceptance Criteria

- (1) Item No. 1~9 The product shall meet the electrical specifications in paragraph 5 after being exposed to normal temperature for less than 24 hours in 2 hours or more
- (2) Item No. 10 The product shall meet the rating.
- (3) Item No. 11~14 There shall be no trouble in testing and the electrical characteristics in paragraph 5 shall be met.

11. Cautions and warnings

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